

*SI Module*  
*for*  
*DeConvEELS*  
(Software Monochromator)

*DigitalMicrograph Plugin*  
*for*  
*Electron Energy Loss Spectrum Deconvolution*

*User's Guide*

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# 1. Introduction

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The SI Module for DeConvEELS is an extension module for DeConvEELS to deconvolute a 3D Spectrum Image (SI) efficiently using Maximum Entropy Method (MEM) or Richardson-Lucy Algorithm (RLA). The principles and practices of processing are the same as used in DeConvEELS. Thus, this Guide assumes the user is familiar with DeConvEELS.

## 1.1 Features

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### 1.1.1 Advanced deconvolution algorithms

The SI Module uses a Maximum Entropy Method (MEM) or the Richardson-Lucy Algorithm (RLA) to deconvolute an EELS Spectrum Image (SI) data. Due to optimized implementation and multi-CPU support an ideal result will be obtained within a reasonably short processing time.

### 1.1.2 Easy-to-Use User Interface

Like DeConvEELS software the SI Module is easy to use and normally works with default setups. However, the user can change its setups easily within a custom-made setup dialog (See [sections 2.2 and 2.3](#)).

**NOTE** Image points and spectra length of *any size* can be handled (not necessary to be a power of two).

The spectrum size of a kernel (low-loss spectrum) and data to be processed should be of equal length.

A kernel may be a single spectrum or a SI data (DualEELS data). If the kernel is a single spectrum, the same kernel will be used for all the spectrum of the SI data. If the data set is a DealeEELS, the corresponding kernel is used for each spectrum to be processed.

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## 2. SI Module

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The SI Module for DeConvEELS consists of a suite of menu commands and a dynamic link library.

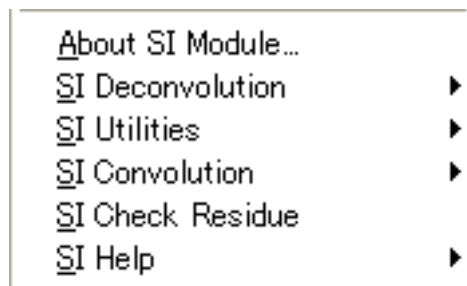
### 2.1 SI Module Commands

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The SI Module commands will appear below DeConvEELS commands as shown below.

Figure 2-1

SI Module commands below DeConvEELS commands



Various control parameters for Maximum Entropy or Richardson-Lucy deconvolution processing will be specified through a dialog that will be opened by selecting a corresponding command.

**TIPS** It is highly recommended to process a single spectrum from the SI data, and find good processing conditions, before processing the whole SI data. The conditions used in a previous processing will be transferred to the SI Deconvolution routine.

Most of the usage of the SI Module commands is similar to the corresponding DeConvEELS commands. Thus, this manual focuses on specific features of the SI module.

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## 2.2 Maximum Entropy Setup

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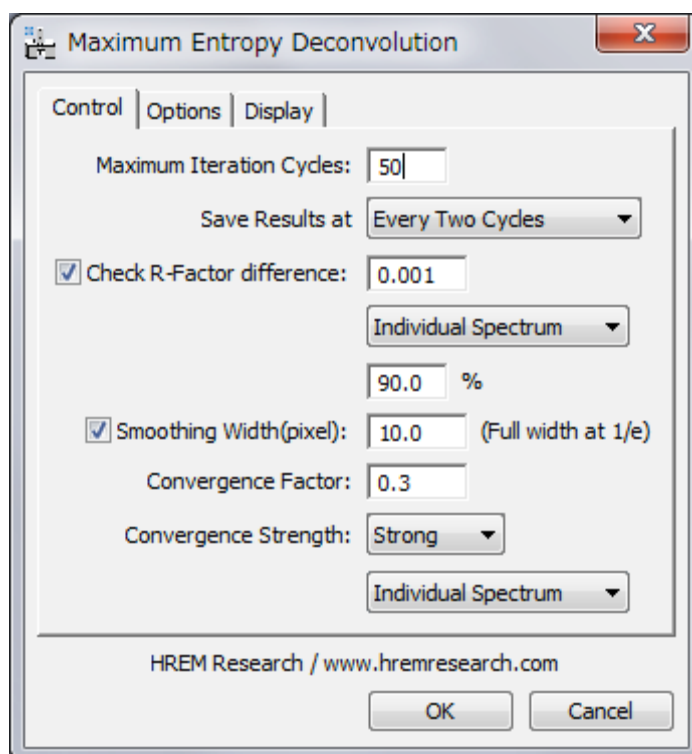
The Maximum Entropy command will open a dialog to control the processing and display the results.

### 2.2.1 Control tab-panel

The front most tab-panel has some general controls for deconvolution processing.

Figure 2-2

Maximum Entropy Deconvolution (Control Tab)



**Maximum Iteration Cycles:** Maximum number of iteration cycles.

**Save Results at:** This controls a frequency of saving the results during the progress of deconvolution. Since the result at each cycle is also a SI data, the ResultLog is a kind of 4D data, and its size may become very large. Thus, the result at each specified cycle is saved as an individual SI data in the folder specified in "Display" tab.

**Check R-Factor difference:** When selected, the iteration will stop when the difference of R-Factor divided by the R-Factor itself becomes smaller than the value specified here.

**\*There are two choices to test convergence criteria:**

*Individual Spectrum:* The iteration will stop, when more than the specified percentage of individual spectrum satisfy the criteria.

*Whole Spectrum:* The iteration will stop, when the SI data as a whole satisfies the criteria.

**Smoothing Width (Full width at 1/e):** When selected, the raw data will be smoothed out by convoluting a Gaussian with a specified half-width (in pixels).

**Convergence Factor:** This controls a speed of convergence.

**Convergence:** There is a selection of convergence between Strong and Weak. The default setting is Strong.

**\*The convergence mode will be applied to individual spectrum or the whole spectrum.**

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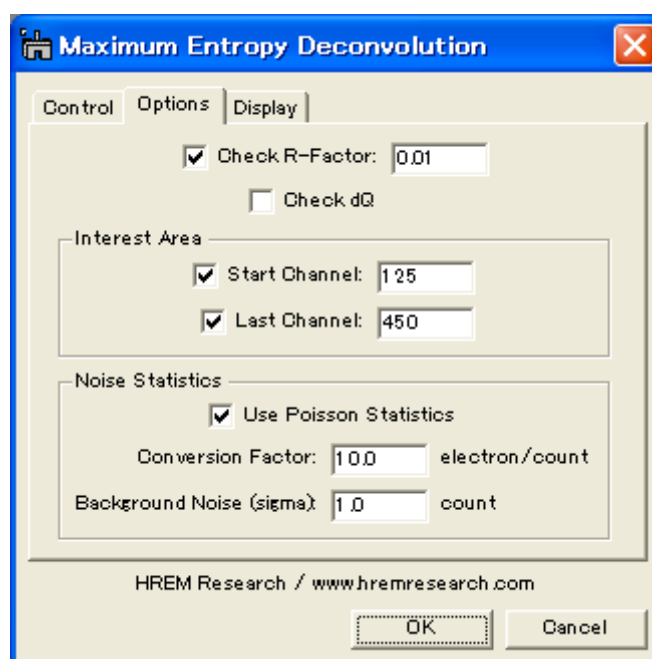
**TIPS** It is highly recommended to process a single spectrum from the SI data, and find good processing conditions, before processing the whole SI data. Then, the same processing conditions will be transferred to the SI Deconvolution routine.

## 2.2.2 Options tab-panel

The next tab-panel is designed for specifying some optional controls for deconvolution processing. This control tab is identical to the one for DeConvEELS.

Figure 2-3

Maximum Entropy Deconvolution (Options Tab)



**Check R-Factor:** When selected, the iteration will stop when R-Factor becomes smaller than the value specified here. It is not recommended to activate this criterion, when you don't know an approximate noise level.

**Check dQ:** When checked, the iteration will stop when the difference of Q value starts oscillating.

**Interest Area:** You can specify an interest area of your spectrum by holding-down and drag the mouse. This is useful for deconvolution of a low-loss area, since convergence testing will not be affected by the dominant zero-loss area.

**Noise Statistics:** You can explicitly use Poisson Statistics for noise distribution. In this case you have to specify Conversion Factor in order to convert a signal count to a number of electrons. You can specify also a constant Background Noise (Gaussian) such as a read-out noise.

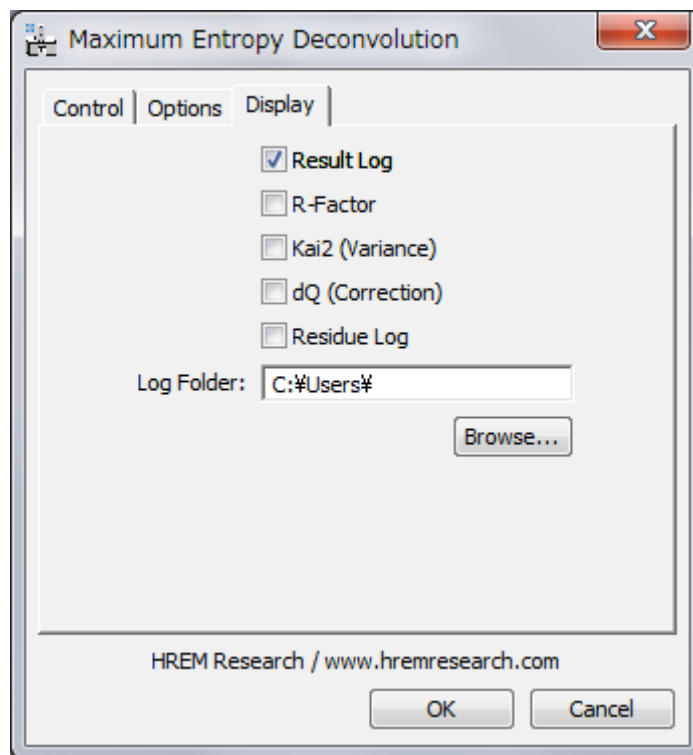
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### 2.2.3 Display tab-panel

The last tab-panel is designed for selecting the various results to be displayed at the end of processing.

Figure 2-4

Maximum Entropy Deconvolution (Display Tab)



**Result Log:** All the intermediate results specified by “Save Results at” will be saved with a name ResultLogxxxx.dm3, where xxxx is a cycle number.

**R-Factor:** History of R-factor.

$\chi^2$  (Variance): History of squared sum of differences.

**dQ (Correction):** History of sum of absolute corrections.

**Residue Log:** All the intermediate residues specified by “Save Results at” will be saved with a name ResidueLogxxxx.dm3, where xxxx is a cycle number.

**Log Folder:** The result at specified cycle is saved as an individual SI data in the folder specified here. You can choose a folder or create a new folder by browsing the directory tree using “Browse” button.

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## 2.3 Richardson-Lucy Setup

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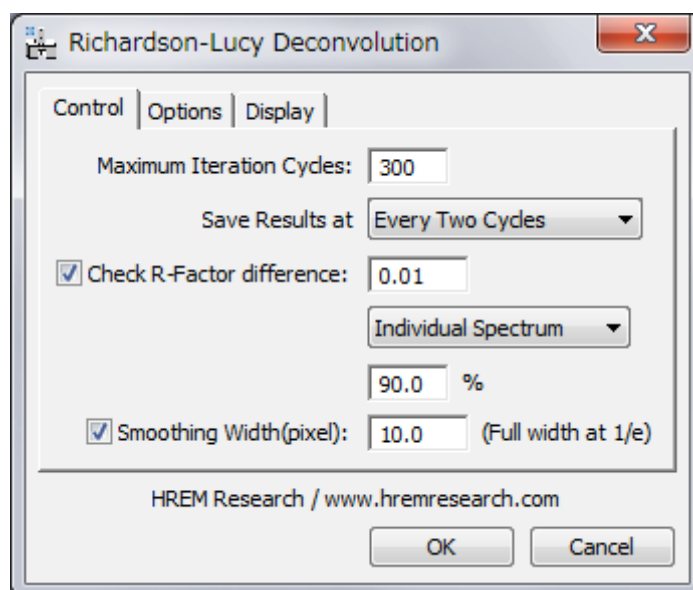
The Richardson-Lucy command will open a dialog to control the processing and display the results.

### 2.3.1 Control tab-panel

The front most tab-panel has some general controls for deconvolution processing.

Figure 2-5

Richardson-Lucy Deconvolution (Control Tab)



**Maximum Iteration Cycles:** Maximum number of iteration cycles.

**Save Results at:** This controls a frequency of saving the results during the progress of deconvolution. Since the result at each cycle is also a SI data, the ResultLog is a kind of 4D data, and its size may become very large. Thus, the result at each specified cycle is saved as an individual SI data in the folder specified in "Display" tab.

**Check R-Factor difference:** When selected, the iteration will stop when the difference of R-Factor divided by the R-Factor itself becomes smaller than the value specified here.

There are two choices to test convergence criteria:

*Individual Spectrum:* The iteration will stop, when more than the specified percentage of individual spectrum satisfy the criteria.

*Whole Spectrum:* The iteration will stop, when the SI data as a whole satisfies the criteria.

**Smoothing Width (Full width at 1/e):** When selected, the raw data will be smoothed out by convoluting a Gaussian with a specified half-width (in pixels).

**TIPS** It is highly recommended to process a single spectrum from the SI data, and find good processing conditions, before processing the whole SI data. Then, the same processing conditions will be transferred to the SI Deconvolution routine.



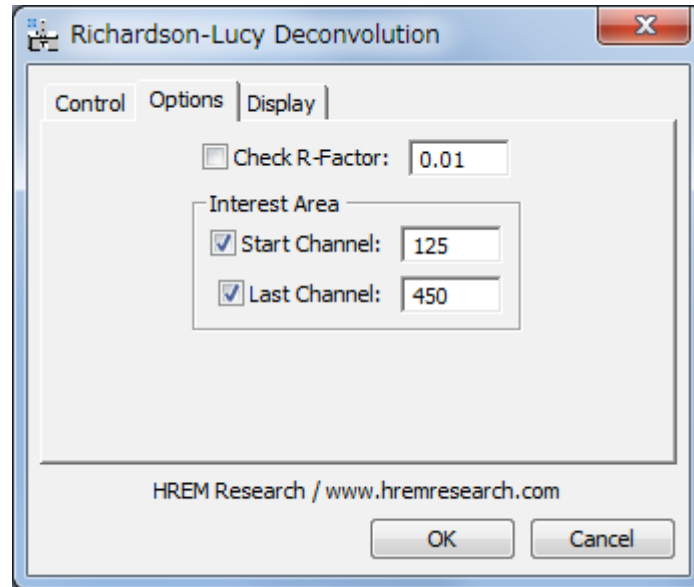
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### 2.3.2 Options tab-panel

The next tab-panel is designed for specifying some optional controls for deconvolution processing. This control tab is identical to the one for DeConVEELS.

Figure 2-6

Richardson-Lucy Deconvolution (Option Tab)



**Check R-Factor:** When selected, the iteration will stop when R-Factor becomes smaller than the value specified here. It is not recommended to activate this criterion, when you don't know an approximate noise level.  
**Interest Area:** You can specify an interest area (ROI; a region of interest) of your spectrum. This is useful for deconvolution of a low-loss area, since convergence testing will not be affected by the dominant zero-loss area.

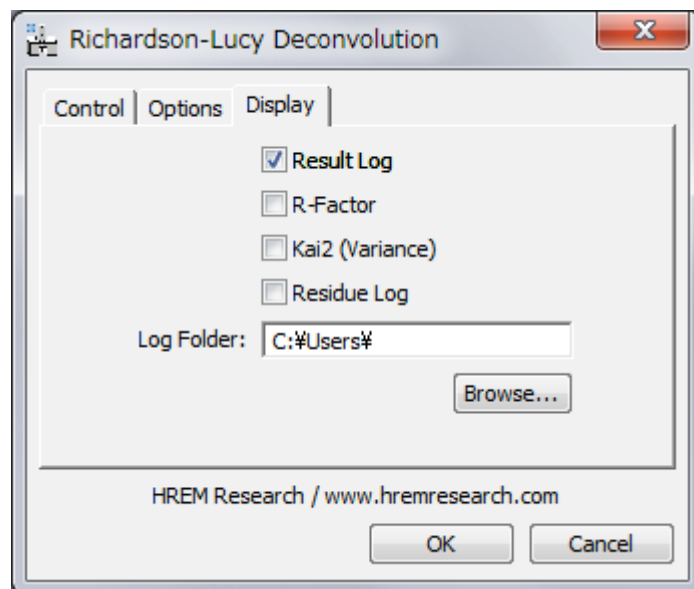
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### 2.3.3 Display tab-panel

The last tab-panel is designed for selecting the various results to be displayed at the end of processing.

Figure 2-7

Richardson-Lucy Deconvolution (Display Tab)



**Result Log:** All the intermediate results specified by “Save Results at” will be saved with a name ResultLogxxxx.dm3, where xxxx is a cycle number.

**R-Factor:** History of R-factor.

**$\chi^2$  (Variance):** History of squared sum of differences.

**Residue Log:** All the intermediate residues specified by “Save Results at” will be saved with a name ResidueLogxxxx.dm3, where xxxx is a cycle number.

**Log Folder:** The result at specified cycle is saved as an individual SI data in the folder specified here. You can choose a folder or create a new folder by browsing the directory tree using “Browse” button.

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## 3. Installation

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This chapter describes hardware and software requirements to run the SI Module for DeConvEELS software and an installation procedure.

### 3.1 Requirements

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The SI Module for DeConvEELS runs under DigitalMicrograph environment, and the software and hardware requirements are similar to those for the DeConvEELS.

#### 3.1.1 Hardware requirement

Since the SI Module for DeConvEELS handles a Spectrum Image (SI) data, it requires an enough memory to store the SI data itself and its deconvoluted result. It is recommended to use a PC with a multi-CPU (Core), since SI processing is number crunching.

#### 3.1.2 Software requirement

The SI Module for DeConvEELS requires DeConvEELS:

### 3.2 Software Installation

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The following plug-ins should be placed in the folder “PlugIns” on the same level of the DigitalMicrograph for Windows:

- **DeConvEELS\_SI.gtk**
- **DeConvEELS\_SI.dll**

Menu commands for SI processing will be appeared below DeConvEELS, when the DigitalMicrograph is launched after placing the plug-ins the PlugIns folder.

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## 4. Getting Started...

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This chapter briefly explains typical steps of Spectrum Image (SI) deconvolution. Before doing this section, you have to install the SI Modules for DeConvEELS.

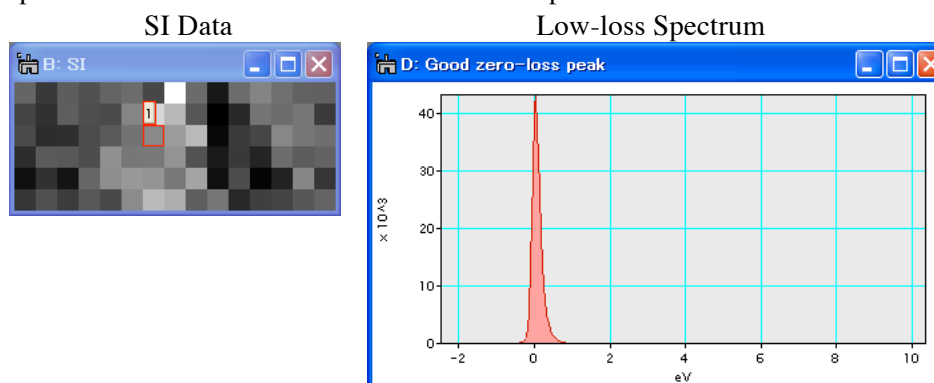
### 4.1 Deconvolution

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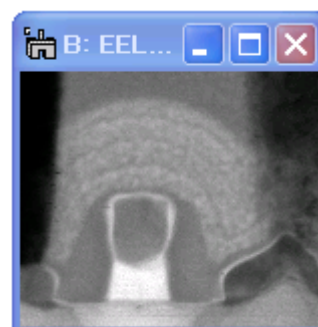
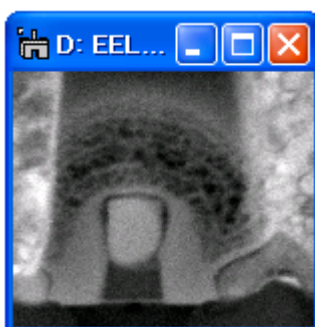
This section briefly describes the steps of SI deconvolution using the Maximum Entropy method. Deconvolution using the Richardson-Lucy algorithm follows the same steps.

#### 4.1.1 Open Spectrum

The deconvolution routine will work on open images. Therefore, you must open an SI data to be restored and a low-loss spectrum as a kernel function.



You can also process an opened DualEELS data pair as shown below:



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## 4.1.2 Establish Deconvolution Conditions

**Before doing deconvolution of the whole SI data/DualEELS data, it is recommended to establish deconvolution conditions using a single spectrum. Then, the same conditions will be transferred to the SI Deconvolution routine.**

### SI Data

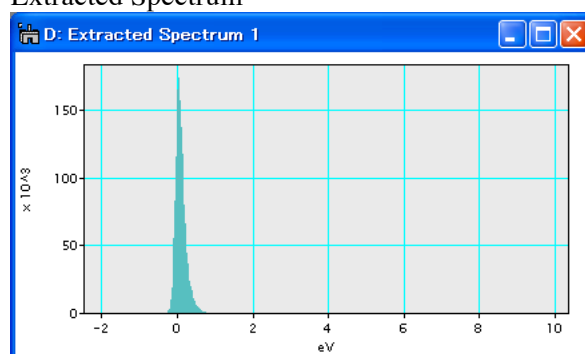


A spectrum to be processed can be extracted from the SI data by using “Spectrum Picker Tool.”



A single spectrum to be processed can also be extracted from the SI data by using the HREM mouse tool and then using “Get Single Spectrum” of Utility Command.

### Extracted Spectrum



This extracted spectrum can be processed with the low-loss spectrum with DeConvEELS to establish the deconvolution conditions.

### DualEELS Data



A pair of high-loss and low-loss spectrum to be processed can be extracted from the DualEELS data by using “Spectrum Picker Tool” and then using “Mirror Extract ROI(s)” command of the EELS plug-in.



A pair of high-loss and low-loss spectrum to be processed can also be extracted from the DualEELS data by using the HREM mouse tool and then using “Get Single Spectrum” of Utility Command.

A pair of extracted high-loss and low-loss spectrum can be processed with DeConvEELS to establish the deconvolution conditions.

## 4.1.3 Launch SI Deconvolution

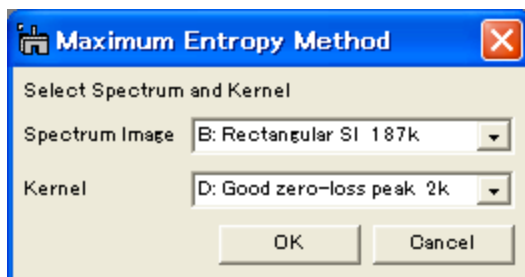
Select “Maximum Entropy” or “Richardson-Lucy” command from the SI Deconvolution menu as shown below. Here, we use the MEM as an example.



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#### 4.1.4 Select Spectrum

Select Spectrum and Kernel from the image list, and click OK to continue processing, or click Cancel to stop the procedure.



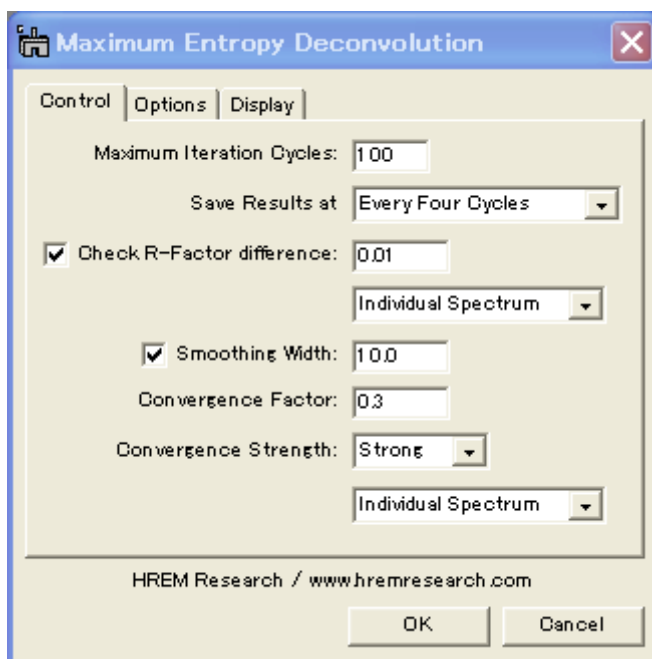
#### 4.1.5 Setup Deconvolution Parameters

**You can setup Deconvolution parameters using the dialog below. However, it is advisable to establish the deconvolution conditions based on a single spectrum by using DeConvEELS routine.**

##### 4.1.5.1 Control Tab

There are two additional parameters specific to the SI deconvolution. Namely, Convergence criteria and the "Convergence Strength" can be applied to each spectrum or the SI data as a whole.

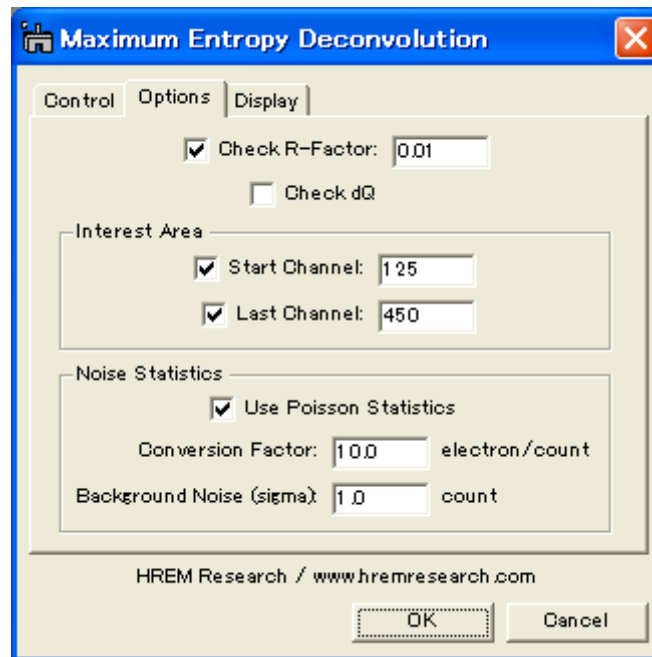
Since the size of result of the SI deconvolution is large, you can change the cycle to save the Results. However, if you want, you can save all the intermediate Results, since the Result will be saved on the hard disk.



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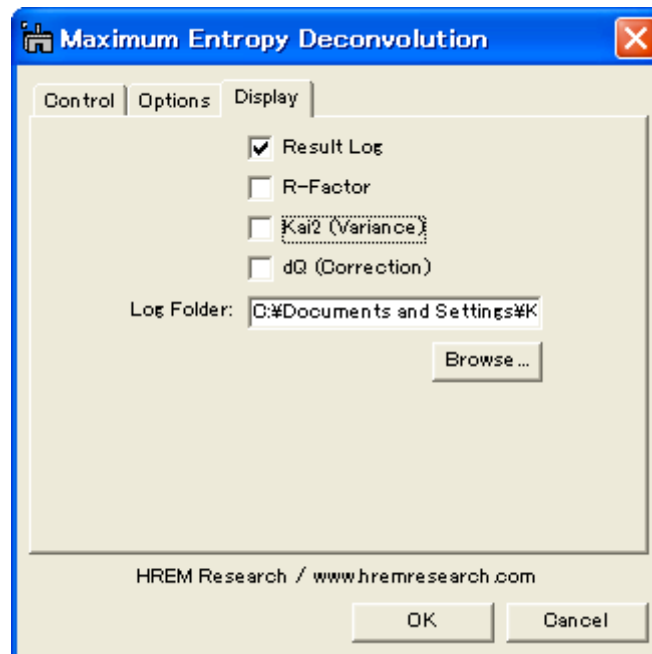
#### 4.1.5.2 Options Tab

There is no additional parameter specific to the SI deconvolution.



#### 4.1.5.3 Display Tab

There is one additional parameter specific to the SI deconvolution. You can choose a folder or create a new folder to save the ResultLog(s).

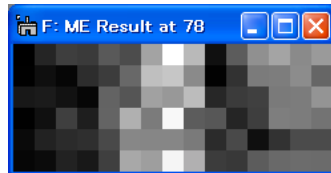


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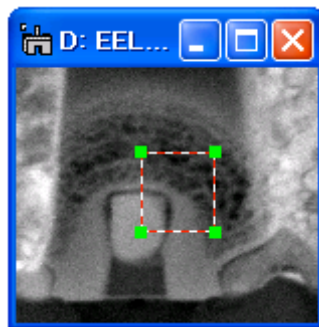
### 4.1.6 Start Deconvolution

After setting conditions, you can start deconvolution by clicking OK button, or stop the procedure by clicking Cancel button at the bottom of the setup dialog.

The result of restored spectrum will be displayed at each cycle as shown below. Since the result is also an SI image, namely a 3D image, the intermediate results at specified cycles will be saved in the selected folder, if you select “Result Log” check box in the setup dialog.



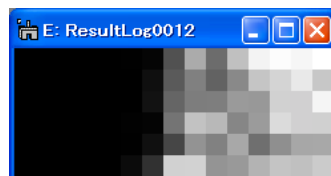
**TIPS** You can use a ROI as show below to select the points to be processed.



### 4.1.7 Survey Results

The final result is displayed in the restored spectrum window as shown above. Some information on the progress of deconvolution will be shown in the DigitalMicrograph's Results Window.

If you select “Result Log” check box in the setup dialog, then, you can open one of the ResultLog file, and survey it as a regular SI data.





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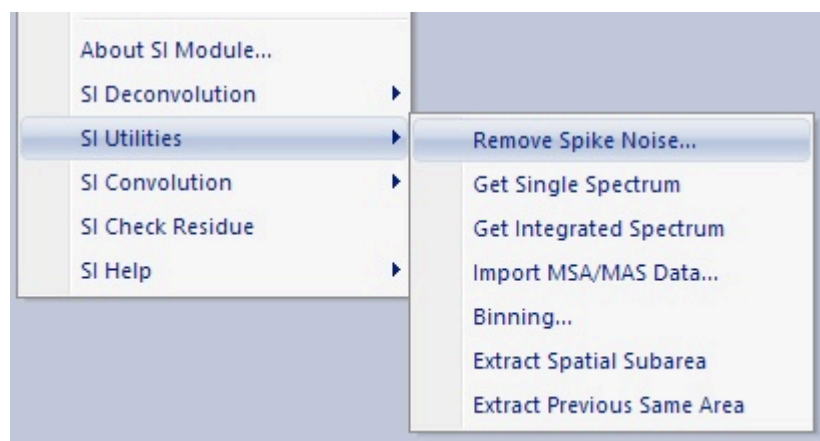
## 4.2 Utilities

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Some useful commands to pre-process or post-process a spectrum are provided for your convenience.

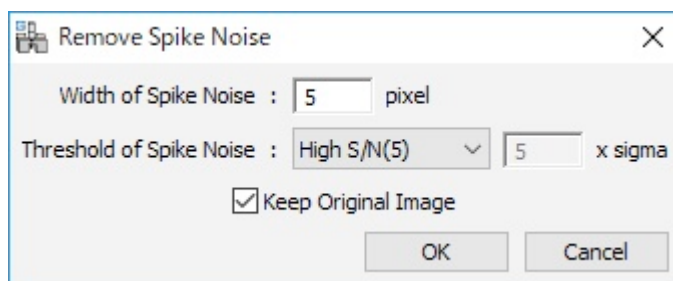
### 4.2.1 Utilities Menu

The following shows the "Utilities" sub-menu.



### 4.2.2 Remove Spike Noise

Using this command you can remove a spike noise(s) from a SI data. A spike noise is defined as the data point that shows an abnormal value. Such a point is created, for example, by cosmic rays. The dialog below appears to set processing parameters.



The spike noise is searched within a specified range of pixels (Width of Spike Noise). The data point that exceeds the specified noise level (Threshold of Spike Noise) is recognized as the spike noise, and replace by the local average.

The number of the removed spike noise will be shown in the dialog, and displayed in the Results (Output) window.

### 4.2.3 Get Single Spectrum



Using this command you can extract a single spectrum from a SI data, or a pair of single high-loss and low-loss spectrum from the DualEELS data at the point selected with the HREM mouse tool.

If you select more than one point, a set of spectrum will be extracted from the points selected with the HREM mouse tool. The extracted spectra will be discriminated by the serial number after the data name.

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## 4.2.4 Get Integrated Spectrum

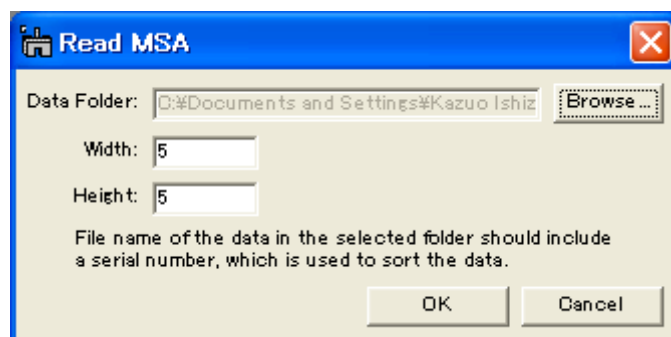
Using this command you can integrate spectra within the area defined by a ROI into a single spectrum. In the case of DualEELS data you can integrate spectra within the same area of high-loss and low-loss spectrum into a pair of the spectra, respectively.

Here, the integrated area for a line-scan data is defined by the top and bottom of a Line ROI or a Rectangular ROI. In the case of 2D scan data the integrated area is obviously inside of a Rectangular ROI.

## 4.2.5 Import MSA/MAS Data...

Using this command you can convert a set of MSA/MAS data to an SI data, which can be processed with the SI Module for DeConvEELS.

When you select this command, the following dialog will open:



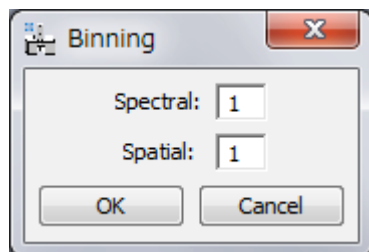
Here, you can select the folder that stores a set of MSA/MAS data, and the numbers of columns (width) and rows (height) of the data. Please note that all the spectra in the folder will be read, and thus the number of spectra in the folder should be equal to (width) x (height). Furthermore, the file names should include a serial number that is used to sort the data.

The serial number may be a set of figures, or two sets of figures separated by non-number character(s). In the latter case, the two sets of figures may correspond to the column and row numbers. The possible file name will be: sample9999, sample\_9999, sample999\_999, sample\_999\_999, column999row999, column999\_row999, where “9” indicates a figure (digit), and you can use any non-number character(s) for a separator.

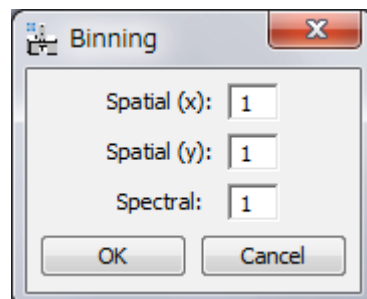
---

## 4.2.6 Binning...

Using this command you can bin an SI data spectrally and spatially. In the case of a DualEELS data both high-loss and low-loss spectrum data will be binned in the same way.



Line-scan data



2D scan data

## 4.2.7 Extract Spatial Subarea

Using this command you can extract a spatial subarea defined by a ROI. In the case of DualEELS data a pair of spatial subareas will be extracted from high-loss and low-loss spectrum, respectively.

Here, for a line-scan data the spatial subarea is defined by the top and bottom of a Line ROI or a Rectangular ROI. In the case of 2D scan data the spatial subarea is obviously inside of a Rectangular ROI.

## 4.2.8 Extract Previous Same Area

Using this command you can extract the same spatial subarea defined by previous **Extract Spatial Subarea** command.

This command will be especially useful for Spatially Resolved (SR) EELS, where a set of high-loss and low-loss spectrum data is acquired from a narrow sample area perpendicular to the energy dispersion. Thus, a SR EELS spectrum is similar to a line-scan SI data.

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## 4.3 Convolution

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Two convolution routines are provided for your convenience.

### 4.3.1 Convolution Menu

The following shows the "Convolution" sub-menu.

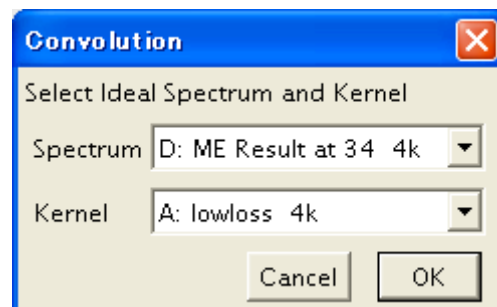


### 4.3.2 Kernel

You may check your result by convoluting the restored spectrum and the kernel function (low-loss spectrum) with the same way as used for DeConvEELS. The convolution should be close to the observed spectrum for a good deconvolution.

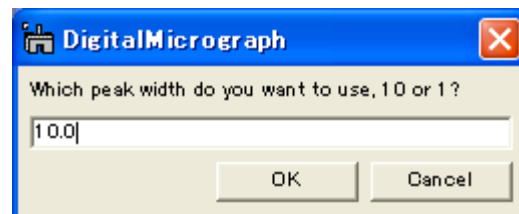
When you want to get a convolution for a final result or an intermediate result (ResultLog), just select these SI data, and next choose this command. Then, a result of convolution will be displayed. This is because the final result keeps information of the Kernel function.

When you want to get a convolution for other than the final or intermediate result, you have to specify a kernel image. In this case, the following windows to select images will appear, when you select the "Convolution" -> "Kernel" command. You have to open the images to be convoluted beforehand.



### 4.3.3 Smoothing Gaussian

Using this command you can check a smoothed spectrum that will be used at deconvolution when you choose the Gaussian smoothing. When the smoothing widths specified for the MEM and RLA are different, you may be asked the value you want to use.



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## 4.4 Check Residue

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You can check residue for a result of deconvolution with the same way as used for DeConvEELS. The residue should be a random noise for a good deconvolution.

When you want to check a residue for a final result or an intermediate result (ResultLog), just select these SI data, and next choose this command. Then, a residue will be displayed. This is because the final result keeps information of the original observed spectrum and the Kernel function.

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# 5. SR-EELS

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This chapter describe how to analyze the SR-EELS data using SI-module for DeconvEELS.

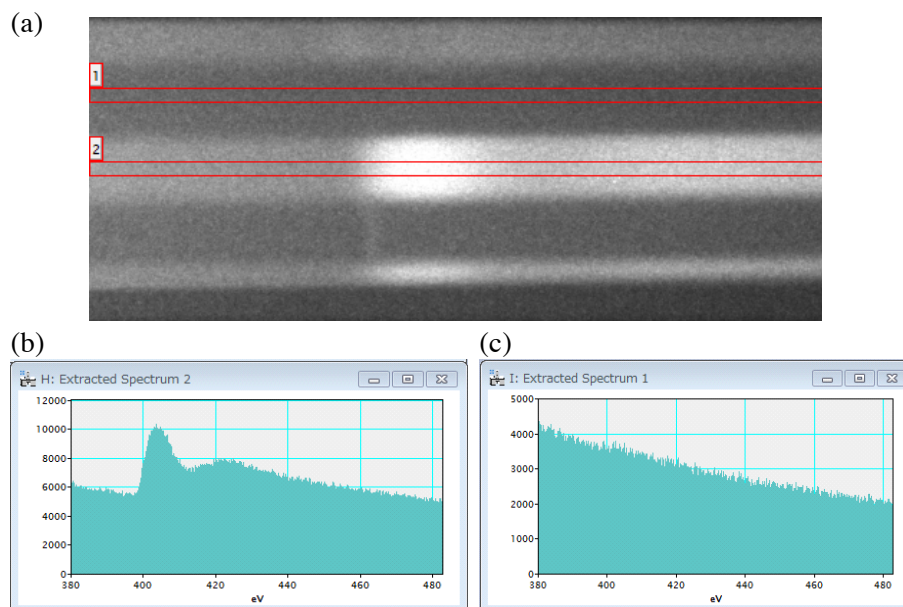
## 5.1 SR-EELS

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### 5.1.1 Introduction

Spatially resolved (SR) EELS is a technique to obtain many EELS data along one line direction in a TEM. An SR-EELS data is similar to the one dimensional SI EELS data which can be obtained by STEM. Typical SR-EELS data is shown below. The horizontal axis of SR-EELS data is energy dispersion axis in energy loss spectroscopy; the vertical axis of the data indicates specimen positions along one-dimensional line in an image. SR-EELS data can be obtained using a selected area slit aperture and line focus technique of EELS.

Details of experimental procedure and applications of this technique are described in some articles, see for example Ref [1]. SR-EELS technique is useful to investigate EELS data along the direction perpendicular to interfaces, grain boundary, layered structures, etc. In the following subsection we describe how to process SR-EELS data using SI module.



(a) Typical SR-EELS data obtained from a layered structure includes nitrogen at some positions. (b) Integrated EELS data obtained from the region 1 which is specified by the two red lines. (c) Integrated EELS data obtained from the region 2 in the SR-EELS data. Nitrogen K-edge can be seen.

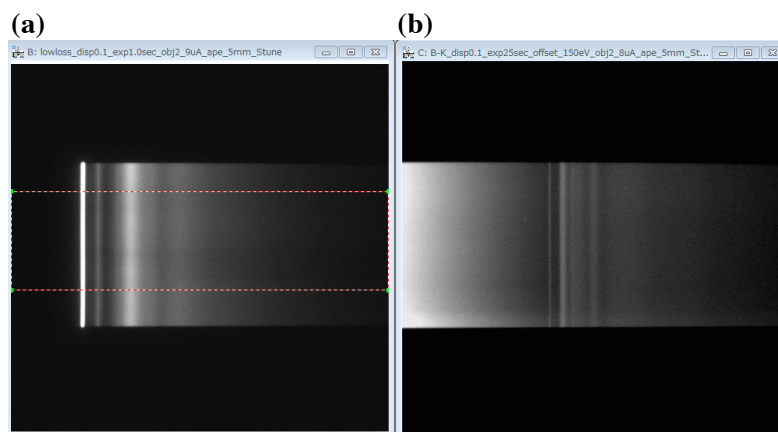
#### Reference

[1] K Kimoto, S Isakozawa, T Aoyama and Y Matsui; *J Electron Microscopy* **50** 523-528 (2001).

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## 5.1.2 Extraction of SR-EELS data

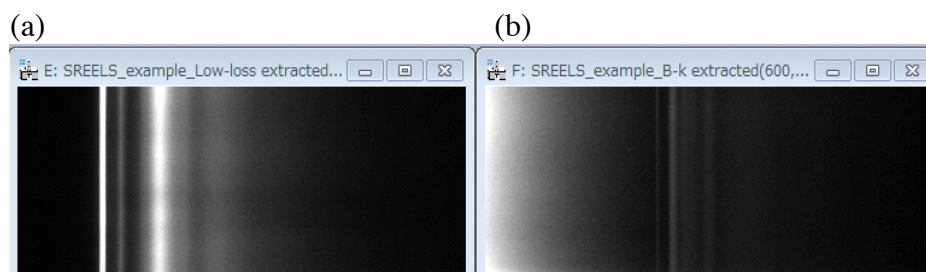
We can extract an SR-EELS from experimental raw SR-EELS, so that all the utility in SI module can be used for the extracted data. This subsection briefly explains how to extract SR-EELS data from the experimentally obtained raw SR-EELS data.



(a), (b) raw SR-EELS data of low-loss and Boron K-edge obtained from BN uniform crystal, respectively. Horizontal axes of these SR-EELS are energy dispersive axes; the vertical axes express different positions along one-dimensional line in a specimen.

Figures above show raw SR-EELS of low-loss and that around Boron K-edge from a uniform BN crystal, respectively. We pick up our interesting area from these raw data. To specify our interesting area we use the rectangular ROI tool of DigitalMicrograph. The above Fig. (a) shows that the ROI tool is on the raw SR-EELS data. Then click “*Extract Spatial Subarea*” in the pull down menu of SI Utilities. The command “*Extract Spatial Subarea*” is explained in the section 4.2.6. Then, a new image shown in below Fig. (a) appears. This image shows the extracted SR-EELS data.

Next, let’s extract an SR-EELS data from the raw Boron-K-edge data. Bring the Boron K-edge raw data shown in above Fig. (b) to the front. Then, click “*Extract Previous Same Area*”! The command “*Extract Previous Same Area*” is explained in 4.2.7. A new image shown in below Fig. (b) appears. This is an extracted SR-EELS data from the raw Boron K-edge data. This Figure has the same sizes, and the same position as that in Fig. (a). Now the extracted data shown in below can be processed by all utilities of SI module for DeConvEELS.



(a), (b), Extracted Low loss, Boron K-edge SR-EELS data from the raw data of BN, respectively.

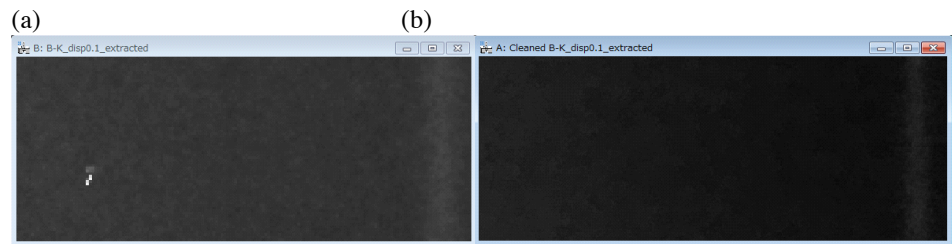
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## 5.2 Remove Spike Noise

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### 5.2.1 Application of Filters

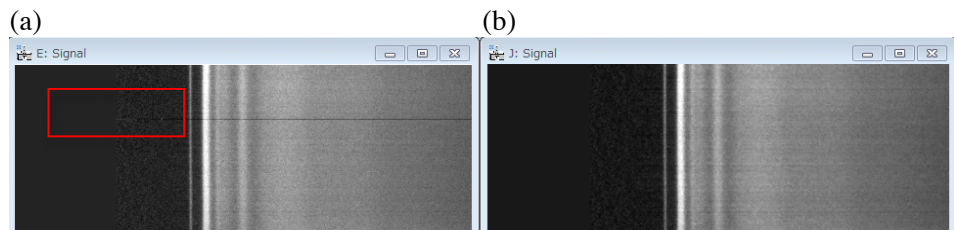
HREM-Filters Pro/Lite is a plug-in for Gatan DigitalMicrograph. Spike noises in experimentally obtained SR-EELS data may be eliminated by using this plugin. In this subsection we show some applications of the HREM-Filter as a pre-process for MSA and/or SI deconvolution. Please consult the user's guide for HREM-Filters Pro/Lite on the details. By applying this program improvements in quality of the processed data can be shown.



(a) An enlarged image of SR-EELS data of Boron K-edge. A spotty bright noise can be seen. (b) The enlarged image of the SR-EELS data at the same position as (a), but after the Filtering process. The noise is eliminated.

Figure above shows an enlarged image of SR-EELS data from Born K-edge. A spotty noise can be seen at the lower left of the Fig. (a). This noise is caused by bad pixels of a CCD camera or due to uncontrollable x-ray or cosmic ray. This noise degrades the quality of data after various processing. If you have installed the HREM-Filter plug-in program, let's select "Filter" at the menu bar, and choose "Replace Dud Pixels"! Then, put appropriate dud pixels size in a dialog box, and press OK! A new SR-EELS data without the contrast at the dud pixels as shown in above Fig. (b) will appear.

Figure below (a) shows the result of SI-deconvolution without the "Replace Dud Pixels" process. You can see the appearance of dark horizontal line that is caused by the spotty noise shown in the above figure (a). This dark horizontal line appears after the subtraction of background, and it gives degradations of data in the following processes. The red rectangular in the above figure. Figure below (b) is the results of the SI-deconvolution with the process of "Replace Dud Pixels". No dark line can be seen. Using "Replace Dud Pixels" as a pre-process can keep the quality of the data for various following process.



(a) A result after SI-deconvolution without the filtering process. (b) A result after SI deconvolution with the filtering process. The red rectangular in (a) indicates the enlarged area shown in the above figure with the spike noise.



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## 6. Tips and Troubleshooting

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### 6.1 Improvement of SI EELS data using MSA

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#### 6.1.1 Introduction

The multivariate statistical analysis (MSA) performs principle component analysis (PCA) to 2D or 3D spectrum image (SI) of such as EDX and EELS. This is a very powerful technique to improve the signal to noise ratio in SI data. In PCA the SI data is decomposed into linearly independent components. We select some numbers of the principal components, and distinguish from other small components that we regard as noise, and then we reconstruct the data from the selected numbers of the components.

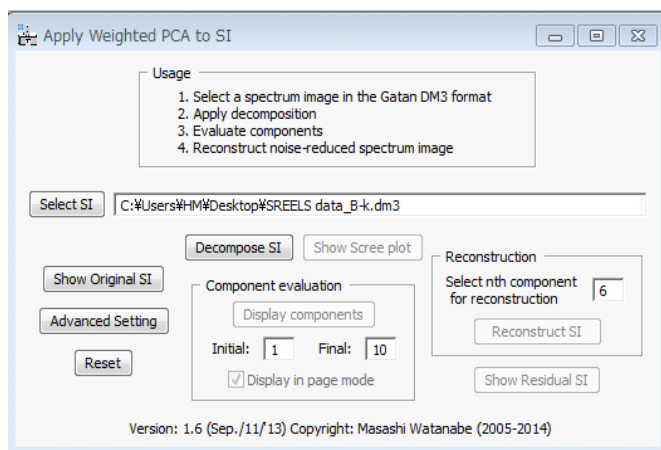
MSA software is released from HREM research Inc. as a plug-in program of DigitalMicrograph. Please, consult the user's guide of MSA on details of how it works and how to use the MSA program.

#### 6.1.2 Process by MSA

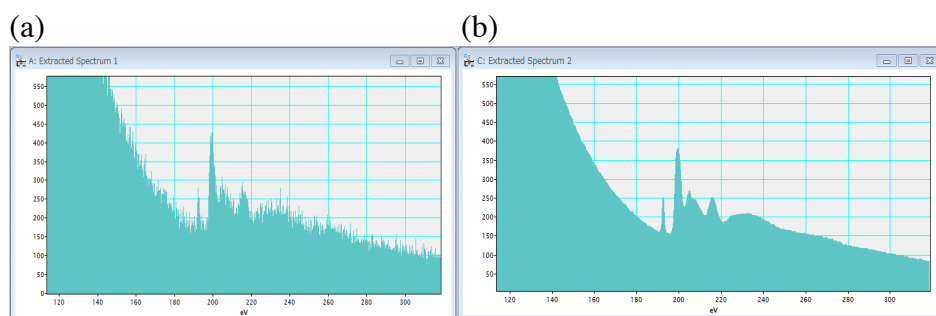
If you have installed MSA plug-in program, the MSA is on the menu bar of DigitalMicrograph. Figure below shows the pull-down menu of "MSA". Choose "MSA" in this menu, and then select "Weighted PCA"!



Then, a dialog box for weighted PCA will appear.



By following the procedure described in the user's guide for “MSA”, we can reconstruct the SR-EELS data with improves signal to noise ratio. Figures below shows a single EELS spectrum of Boron K-edge (a) without the MSA process, and (b) with the MSA process. The MSA is effective as a pre-process for DeConvolution.



Single spectrum of Boron K-edge (a) without MSA process (b) with MSA process